TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

TC7MZ540FK

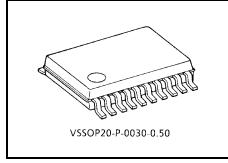
Low Voltage Octal Bus Buffer (inverted) with 5 V Tolerant Inputs and Outputs

The TC7MZ540FK is a high performance CMOS octal bus buffer. Designed for use in 3.3 V systems, it achieves high speed operation while maintaining the CMOS low power dissipation.

The device is designed for low-voltage (3.3 V) $V_{\rm CC}$ applications, but it could be used to interface to 5 V supply environment for both inputs and outputs.

The TC7MZ540FK is an inverting 3-state buffer having two active-low output enables. When either $\overline{OE}1$ or $\overline{OE}2$ are high, the terminal outputs are in the high-impedance state. This device is designed to be used with 3-state memory address drivers, etc.

All inputs are equipped with protection circuits against static discharge.



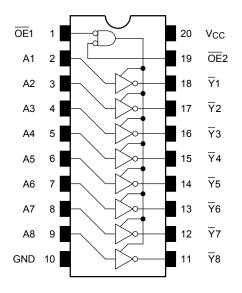
Weight: 0.03 g (typ.)

Features

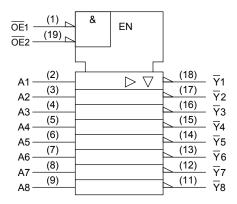
- Low voltage operation: $V_{CC} = 2.0 \sim 3.6 \text{ V}$
- High speed operation: $t_{pd} = 6.5 \text{ ns (max)} (V_{CC} = 3.0 \sim 3.6 \text{ V})$
- Output current: $|I_{OH}|/I_{OL} = 24 \text{ mA (min)} (V_{CC} = 3.0 \text{ V})$
- Latch-up performance: -500 mA
- Package: VSSOP (US20)
- Power down protection is provided on all inputs and outputs.
- Pin and function compatible with the 74 series (74AC/VHC/HC/F/ALS/LS etc.) 540 type.

1 2007-10-19

Pin Assignment (top view)



IEC Logic Symbol



Truth Table

	Inputs					
OE1	OE2	A _n	Outputs			
Н	X	X	Z			
X	Н	Х	Z			
L	L	Н	L			
L	L	L	Н			

X: Don't care

Z: High impedance

Absolute Maximum Ratings (Note 1)

Characteristics	Symbol	Rating	Unit
Supply voltage range	V _{CC}	-0.5~7.0	V
DC input voltage	V _{IN}	-0.5~7.0	V
DC output valte as	V _{OUT}	−0.5~7.0 (Note 2)	V
DC output voltage	VOU1	-0.5~V _{CC} + 0.5 (Note 3)	V
Input diode current	Ι _{ΙΚ}	-50	mA
Output diode current	lok	±50 (Note 4)	mA
DC output current	lout	±50	mA
Power dissipation	PD	180	mW
DC V _{CC} /ground current	I _{CC} /I _{GND}	±100	mA
Storage temperature	T _{stg}	−65~150	°C

Note 1: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 2: Output in off-state

Note 3: High or low state. IOUT absolute maximum rating must be observed.

Note 4: $V_{OUT} < GND, V_{OUT} > V_{CC}$

Operating Ranges (Note 1)

Characteristics	Symbol	Rating	Unit	
Supply voltage	Vcc 2.0~3.6		V	
Supply Voltage	vcc vcc	1.5~3.6 (Note 2)	V	
Input voltage	V _{IN}	0~5.5	V	
Output voltage	Vout	0~5.5 (Note 3)	V	
		0~V _{CC} (Note 4)	V	
Output current	IoH/IoL	±24 (Note 5)	mA	
Output current	iOH/iOL	±12 (Note 6)	IIIA	
Operating temperature	T _{opr}	-40~85	°C	
Input rise and fall time	dt/dv	0~10 (Note 7)	ns/V	

Note 1: The operating ranges must be maintained to ensure the normal operation of the device.

Unused inputs must be tied to either VCC or GND.

Note 2: Data retention only

Note 3: Output in off-state

Note 4: High or low state

Note 5: $V_{CC} = 3.0 \sim 3.6 \text{ V}$

Note 6: $V_{CC} = 2.7 \sim 3.0 \text{ V}$

Note 7: $V_{IN} = 0.8 \sim 2.0 \text{ V}, V_{CC} = 3.0 \text{ V}$

Electrical Characteristics

DC Characteristics ($Ta = -40 \sim 85$ °C)

Characte	Characteristics Symbol Test Condition		Min	Max	Unit							
Ondrade	SHOUGO	Cymbol		rest Condition		IVIIII	IVIAX	Offic				
Input voltage	High level	V _{IH}		_	2.7~3.6	2.0	_	V				
iliput voltage	Low level	V _{IL}		_	2.7~3.6		0.8	٧				
				I _{OH} = -100 μA	2.7~3.6	V _{CC} - 0.2	_					
	High level	V _{OH}	$V_{IN} = V_{IH}$ or V_{IL}	$I_{OH} = -12 \text{ mA}$	2.7	2.2	_					
				$I_{OH} = -18 \text{ mA}$	3.0	2.4	_					
Output voltage				$I_{OH} = -24 \text{ mA}$	3.0	2.2	_	V				
				$I_{OL} = 100 \mu A$	2.7~3.6	_	0.2					
	Low level		$V_{IN} = V_{IH}$ or V_{IL}	$I_{OL} = 12 \text{ mA}$	2.7		0.4					
	LOW ICVCI	LOWICVCI	Lowiever	V _{OL}	AIN = AIH OI AIT	AIM - AIH OI AIL	VIIV — VIII OI VIIL	$I_{OL} = 16 \text{ mA}$	3.0	1	0.4	
				I _{OL} = 24 mA	$I_{OL} = 24 \text{ mA}$	3.0		0.55				
Input leakage cu	ırrent	I _{IN}	V _{IN} = 0~5.5 V		2.7~3.6	1	±5.0	μΑ				
2 state output of	f state current	lo-	$V_{IN} = V_{IH}$ or V_{IL}		2.7~3.6		±5.0					
3-state output off-state current I _{OZ}		V _{OUT} = 0~5.5 V		2.7~3.0		±3.0	μΑ					
Power off leakag	ge current	I _{OFF}	$V_{IN}/V_{OUT} = 5.5 \text{ V}$		0		10.0	μΑ				
Quiescent supply current I _C		Icc	V _{IN} = V _{CC} or GND		2.7~3.6		10.0					
Quicocent suppi	y current	100	V _{IN} /V _{OUT} = 3.6~5.5	V	2.7~3.6		±10.0	μΑ				
Increase in I _{CC}	per input	Δlcc	$V_{IH} = V_{CC} - 0.6 V$		2.7~3.6	_	500					



AC Characteristics ($Ta = -40 \sim 85$ °C)

Characteristics	Symbol	Test Condition	V _{CC} (V)	Min	Max	Unit
Dranagation dalay time	t _{pLH}	Figure 1 Figure 2	2.7	_	7.5	20
Propagation delay time	t_{pHL}	Figure 1, Figure 2	3.3 ± 0.3	1.5	6.5	ns
Output enable time	t _{pZL}	Figure 1, Figure 3	2.7	_	9.5	- ns
	t _{pZH}		3.3 ± 0.3	1.5	8.5	
Output disable time	t_{pLZ}	Figure 1, Figure 3	2.7		8.5	ns
Output disable time	t _{pHZ}	rigure i, rigure 3	3.3 ± 0.3	1.5	7.5	115
Output to output skew	t _{osLH}	(Note)	2.7	_		ns
Output to output sitew	t _{osHL}	(Note)	3.3 ± 0.3	_	1.0	113

Note: This parameter is guaranteed by design.

 $(t_{OSLH} = |t_{PLHm} - t_{PLHn}|, t_{OSHL} = |t_{PHLm} - t_{PHLn}|)$

Dynamic Switching Characteristics

(Ta = 25°C, Input: $t_r = t_f = 2.5$ ns, $C_L = 50$ pF, $R_L = 500$ Ω)

Characteristics	Symbol	Test Condition	V _{CC} (V)	Тур.	Unit
Quiet output maximum dynamic V _{OL}	V _{OLP}	$V_{IH} = 3.3 \text{ V}, V_{IL} = 0 \text{ V}$	3.3	8.0	V
Quiet output minimum dynamic V_{OL}	V _{OLV}	$V_{IH} = 3.3 \text{ V}, V_{IL} = 0 \text{ V}$	3.3	8.0	V

Capacitive Characteristics (Ta = 25°C)

Characteristics	Symbol	Test Condition	V _{CC} (V)	Тур.	Unit
Input capacitance	CIN	_	3.3	7	pF
Output capacitance	C _{OUT}	_	3.3	8	pF
Power dissipation capacitance	C _{PD}	f _{IN} = 10 MHz (Not	e) 3.3	40	pF

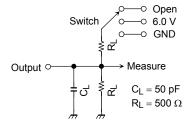
Note: CPD is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption.

Average operating current can be obtained by the equation:

 $I_{CC (opr)} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}/8 \text{ (per bit)}$

AC Test Circuit

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Parameter	Switch
t _{pLH} , t _{pHL}	Open
t_{pLZ} , t_{pZL}	6.0 V
t _{pHZ} , t _{pZH}	GND

Figure 1

AC Waveform

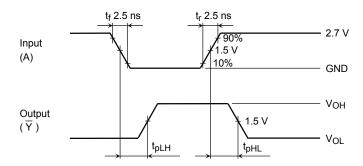


Figure 2 t_{pLH}, t_{pHL}

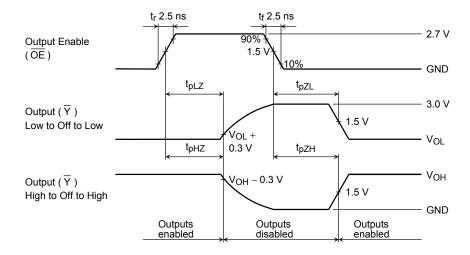
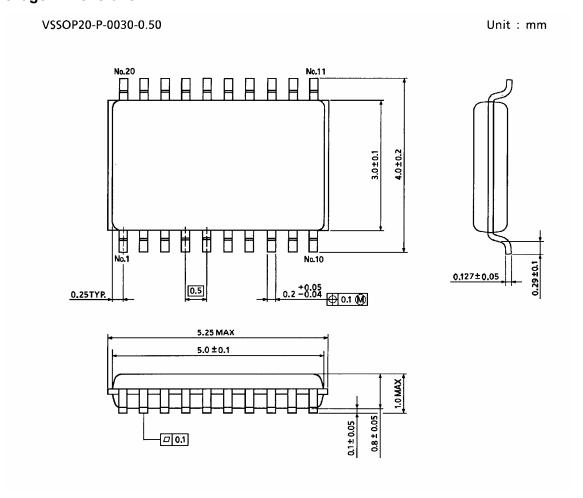


Figure 3 t_{pLZ} , t_{pHZ} , t_{pZL} , t_{pZH}

Package Dimensions

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Weight: 0.03 g (typ.)

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20070701-EN GENERAL

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